Se	arch	Note	S

Application/Control No.	Applicant(s)/Patent under Reexamination
10/602,146	LEE ET AL.
Examiner	Art Unit
Jordany Núñez	2179

	SEAR	CHED	
Class	Subclass	Date	Examiner
715	806	12/22/2006	JN

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East: USPAT, US PGPUB, EPO, JPO, Derwent, IBM-IDB	12/22/2006	JN
NPL	12/22/2006	JN
Consulted with primary examiner, Ba Huynh, AU 2179	12/22/2006	JN